Special Issue

Application of Artificial Neural Network in Non-destructive Testing

Message from the Guest Editor

Artificial Neural Network (ANN) as a mathematical method has powerful role in solving various engineering and management problems for different purposes such as classification and prediction. The necessity of this efficient tool is clearly seen in nonlinear and complex systems. Application of other numerical methods such as feature extraction in time, frequency and time-frequency domain, feature reduction, feature selection, correlation analysis and etc. beside of ANN can improve the efficiency of Non-Destructive Testing (NDT) with any basis for obtaining better result for desired purposes. This Special Issue of Applied Sciences will provide a forum for discussing exciting research on applying different kinds of ANNs such as Feed Forward NN, Radial Basis Function, Kohonen Self Organizing NN, Support Vector Machine, Group Method of Data Handling, Recurrent NN, Convolutional NN and etc. in a variety of domains specially complex problems of NDT. Both original research articles and comprehensive review papers are welcome.

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Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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